Supporting information for article:

Defect engineering by synchrotron radiation X-rays in CeO2 nanocrystals

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**Figure S1** XRD patterns of CeO$_2$ samples annealed at different temperatures and Y-doped CeO$_2$ sample Y1 and Y2. Curves have been shifted vertically for the sake of clarity.

**Figure S2** (a) Ce L$_3$-edge XANES and (b) XRD patterns of CeO$_2$ samples with different x-ray irradiation times.